## DATA SHEET

## TZA3030 <br> SDH/SONET STM1/OC3 optical receiver

Objective specification
File under Integrated Circuits, IC19

## FEATURES

- Low equivalent input noise, typically $1 \mathrm{pA} / \sqrt{ } \mathrm{Hz}$
- Wide dynamic range, typically $0.5 \mu \mathrm{~A}$ to 2 mA
- On-chip low-pass filter. The bandwidth can be varied between 90 and 150 MHz using an external resistor. Default value is 120 MHz .
- Differential transimpedance of $1.8 \mathrm{M} \Omega$
- On-chip Automatic Gain Control (AGC)
- Positive Emitter Coupled Logic (PECL) or Current-Mode Logic (CML) compatible data outputs
- LOS (Loss Of Signal) detection
- LOS threshold level can be adjusted using a single external resistor
- On-chip DC offset compensation
- Single supply voltage from 3.0 to 5.5 V
- Bias voltage for PIN diode.


## APPLICATIONS

- Digital fibre optic receiver in short, medium and long haul optical telecommunications transmission systems or in high speed data networks
- Wideband RF gain block.


## GENERAL DESCRIPTION

The TZA3030 optical receiver is a low-noise transimpedance amplifier with AGC plus a limiting amplifier designed to be used in SDH/SONET fibre optic links. The TZA3030 amplifies the current generated by a photo detector (PIN diode or avalanche photodiode) and converts it to a differential output voltage.

## ORDERING INFORMATION

| TYPE <br> NUMBER | PACKAGE |  |  |
| :--- | :---: | :--- | :---: | :---: |
|  | NAME | DESCRIPTION | VERSION |
| TZA3030HL | LQFP32 | plastic low profile quad flat package; 32 leads; body $5 \times 5 \times 1.4 \mathrm{~mm}$ | SOT401-1 |
| TZA3030U | - | naked die in waffle pack carriers; die dimensions $1.58 \times 1.58 \mathrm{~mm}$ | - |

## BLOCK DIAGRAM



Fig. 1 Block diagram.

## PINNING

| SYMBOL | PIN | TYPE | DESCRIPTION |
| :---: | :---: | :---: | :---: |
| AGND | 1 | ground | analog ground |
| $\mathrm{V}_{\text {CCA }}$ | 2 | supply | analog supply voltage |
| AGND | 3 | ground | analog ground |
| DREF | 4 | analog output | bias voltage for PIN diode ( $\mathrm{V}_{\mathrm{CCA}}$ ); cathode should be connected to this pin |
| $\mathrm{V}_{\text {CCA }}$ | 5 | supply | analog supply voltage |
| AGND | 6 | ground | analog ground |
| IPhoto | 7 | analog input | current input; connect the anode of PIN diode to this pin; DC bias level is 1048 mV |
| AGND | 8 | ground | analog ground |
| AGND | 9 | ground | analog ground |
| BWC | 10 | analog input | bandwidth control pin; default bandwidth is 120 MHz ; a resistor should be connected between $\mathrm{V}_{\text {ref }}$ (pin 11) and BWC (pin 10) to decrease bandwidth, or between BWC (pin 10) and AGND to increase bandwidth |
| $\mathrm{V}_{\text {ref }}$ | 11 | analog output | band gap reference voltage; nominal value approximately 1.2 V |
| SUB | 12 | substrate | substrate pin; to be connected to AGND |
| DGND | 13 | ground | digital ground |
| RFTEST | 14 | analog input | test pin; not connected; not used in application |
| OUTSEL | 15 | CMOS input | output select pin; when OUTSEL is HIGH, CML data outputs are active and PECL data outputs are disabled; OUTSEL is pulled LOW if left unconnected, PECL data outputs will then be active and CML data outputs disabled |
| DGND | 16 | ground | digital ground |
| $\mathrm{V}_{\text {CCD }}$ | 17 | supply | digital supply voltage |
| OUTCML | 18 | CML output | CML data output; OUTCML goes HIGH when current flows into IPhoto (pin 7) |
| OUTQCML | 19 | CML output | CML compliment of OUTCML (pin 18) |
| $\mathrm{V}_{\text {CCD }}$ | 20 | supply | digital supply voltage |
| DGND | 21 | ground | digital ground |
| OUTPECL | 22 | PECL output | PECL data output; OUTPECL goes HIGH when current flows into IPhoto (pin 7) |
| OUTQPECL | 23 | PECL output | PECL compliment of OUTPECL (pin 22) |
| DGND | 24 | ground | digital ground |
| DGND | 25 | ground | digital ground |
| LOS | 26 | PECL output | PECL-compatible LOS detection pin; LOS output is HIGH when the input signal is below the user programmable threshold level |
| LOSQ | 27 | PECL output | PECL compliment of LOS (pin 26) |
| LOSTTL | 28 | TTL output | CMOS-compatible LOS detection pin; the LOSTTL output is HIGH when the input signal is below the user programmable threshold level |
| LOSTH | 29 | analog I/O | pin for setting input threshold level; nominal DC voltage is $\mathrm{V}_{\mathrm{CCA}}-1.5 \mathrm{~V}$; threshold level set by connecting an external resistor between LOSTH and $\mathrm{V}_{\text {CCA }}$ or by forcing a current into LOSTH; default value for this resistor is $400 \mathrm{k} \Omega$ |
| AGND | 30 | ground | analog ground |
| AGC | 31 | analog I/O | AGC monitor voltage; the internal AGC circuit can be disabled by applying an external voltage to this pin |
| AGND | 32 | ground | analog ground |



CHIP DIMENSIONS AND BONDING PAD LOCATIONS

| SYMBOL | PAD | COORDINATES ${ }^{(1)}$ |  |
| :--- | :---: | :---: | :---: |
|  |  | $\mathbf{x}$ | $\mathbf{y}$ |
| AGND | 1 | 102 | 1251 |
| V $_{\text {CCA }}$ | 2 | 102 | 1111 |
| AGND | 3 | 102 | 971 |
| DREF | 4 | 102 | 814 |
| V $_{\text {CCA }}$ | 5 | 102 | 674 |
| AGND | 6 | 102 | 534 |
| IPhoto | 7 | 102 | 395 |
| AGND | 8 | 102 | 254 |
| AGND | 9 | 243 | 105 |
| BWC | 10 | 383 | 105 |
| V $_{\text {ref }}$ | 11 | 523 | 105 |
| SUB | 12 | 663 | 105 |
| DGND | 13 | 803 | 105 |
| RFTEST | 14 | 943 | 105 |
| OUTSEL | 15 | 1100 | 105 |
| DGND | 16 | 1257 | 105 |
| V $_{\text {CCD }}$ | 17 | 1398 | 263 |
| OUTCML | 18 | 1398 | 403 |


| SYMBOL | PAD | COORDINATES ${ }^{(1)}$ |  |
| :--- | :---: | :---: | :---: |
|  |  | $\mathbf{x}$ | $\mathbf{y}$ |
| OUTQCML | 19 | 1398 | 543 |
| V $_{\text {CCD }}$ | 20 | 1398 | 683 |
| DGND | 21 | 1398 | 823 |
| OUTPECL | 22 | 1398 | 963 |
| OUTQPECL | 23 | 1398 | 1103 |
| DGND | 24 | 1398 | 1243 |
| DGND | 25 | 1283 | 1400 |
| LOS | 26 | 1143 | 1400 |
| LOSQ | 27 | 986 | 1400 |
| LOSTTL | 28 | 829 | 1400 |
| LOSTH | 29 | 671 | 1400 |
| AGND | 30 | 514 | 1400 |
| AGC | 31 | 357 | 1400 |
| AGND | 32 | 217 | 1400 |

## Note

1. All coordinates ( $\mu \mathrm{m}$ ) are measured with respect to the bottom left-hand corner of the die.


Fig. 3 Bonding pad locations of TZA3030U.

## FUNCTIONAL DESCRIPTION

The TZA3030 contains five functional blocks:

- Preamplifier input stage
- Low-pass filter
- Limiting amplifier stage
- Offset compensation loop
- Loss of signal detection unit.


## Preamplifier

The preamplifier provides low-noise amplification of the current generated by a photodiode connected to pin IPhoto.

A differential amplifier converts the output of the preamplifier to a differential voltage. An AGC loop increases the dynamic range of the receiver by reducing the feedback resistance of the preamplifier. The AGC loop hold capacitor is integrated on-chip, so an external capacitor is not needed for AGC. The AGC voltage can be monitored at pin AGC. This pin can be left unconnected for normal operation. It can also be used to force an external AGC voltage. If pin AGC is connected to $\mathrm{V}_{\mathrm{CCA}}$, the internal AGC loop is disabled and the receiver gain is at a maximum. In this case, the maximum input current is approximately $10 \mu \mathrm{~A}$.

## Low-pass filter

A low-pass filter controls the bandwidth of the receiver, which can be varied between 90 and 150 MHz . The bandwidth is set to 120 MHz by default. It can be decreased by connecting a resistor between pin BWC and pin $\mathrm{V}_{\text {ref }}$ or increased by connecting a resistor between pin BWC and AGND.

## Limiting amplifier

A limiting amplifier boosts the signal up to PECL levels. The output can be either CML or PECL compatible, selected by means of pin OUTSEL. When OUTSEL is HIGH, the CML data outputs are active and the PECL data outputs are disabled. If OUTSEL is left unconnected, it is pulled LOW and the PECL data outputs are active while the CML data outputs are disabled.

The logic level symbol definitions for CML and PECL are shown in Fig. 4.
The CML and PECL output circuits are given in Fig.5.

## Offset compensation loop

A control loop connected between the limiting amplifier output and the differential amplifier input cancels the DC offset. The loop bandwidth is fixed internally at 30 kHz .

## Loss Of Signal (LOS) detection

The LOS section detects an input signal level below a fixed threshold. The threshold is determined by the current through pin LOSTH. If this current is increased, the threshold level will rise. An external resistor connected between pin LOSTH and $\mathrm{V}_{\text {CCA }}$ can be used, or a current can be forced into pin LOSTH. The default value for the external resistor is $400 \mathrm{k} \Omega$. In this case, the current through pin LOSTH will be approximately $3.75 \mu \mathrm{~A}$ since the voltage at pin LOSTH is regulated at 1.5 V below the supply voltage. This threshold corresponds to an input current of 208 nA . The ratio of LOSTH current to input current is thus approximately $18: 1$. When the input signal level falls below this threshold, the LOS
(PECL compatible) and LOSTTL (TTL compatible)
outputs go HIGH. The hysteresis is fixed internally at 3 dB . Response time is typically less than $20 \mu \mathrm{~s}$.


Fig. 4 Logic level symbol definitions for CML and PECL.


Fig. 5 Output circuits.

## LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

| SYMBOL | PARAMETER | MIN. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: |
| VCC | supply voltage | -0.5 | +6 | V |
| $\mathrm{V}_{\mathrm{n}}$ | DC voltage <br> pin 7: IPhoto <br> pin 14: RFTEST <br> pins 22, 23, 26 and 27: OUTPECL, OUTQPECL, LOS and LOSQ <br> pins 18 and 19: OUTCML and OUTQCML <br> pin 29: LOSTH <br> pin 10: BWC <br> pin 31: AGC <br> pin 11: $\mathrm{V}_{\text {ref }}$ <br> pin 4: DREF <br> pin 15: OUTSEL <br> pin 28: LOSTTL | -0.5 -0.5 $V_{C C}-2$ $V_{C C}-2$ -0.5 -0.5 -0.5 -0.5 -0.5 -0.5 -0.5 | $\begin{aligned} & +2 \\ & V_{C C}+0.5 \\ & V_{C C}+0.5 \\ & V_{C C}+0.5 \\ & V_{C C}+0.5 \\ & +3.2 \\ & V_{C C}+0.5 \\ & +3.2 \\ & V_{C C}+0.5 \\ & V_{C C}+0.5 \\ & V_{C C}+0.5 \\ & \hline \end{aligned}$ | $\begin{aligned} & \mathrm{V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \\ & \mathrm{~V} \end{aligned}$ |
| $\mathrm{I}_{\mathrm{n}}$ | DC current <br> pin 7: IPhoto <br> pin 14: RFTEST <br> pins 22, 23, 26 and 27: OUTPECL, OUTQPECL, LOS and LOSQ <br> pins 18 and 19: OUTCML and OUTQCML <br> pin 29: LOSTH <br> pin 10: BWC <br> pin 31: AGC <br> pin 11: $\mathrm{V}_{\text {ref }}$ <br> pin 4: DREF <br> pin 15: OUTSEL <br> pin 28: LOSTTL | -2.5 -2 -25 -15 -2 -1 -0.2 -2 -2.5 -0.5 -16 | $\begin{aligned} & +2.5 \\ & +2 \\ & +10 \\ & +15 \\ & +2 \\ & +1 \\ & +0.2 \\ & +2.5 \\ & +2.5 \\ & +0.5 \\ & +16 \\ & \hline \end{aligned}$ | mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA <br> mA |
| $\mathrm{P}_{\text {tot }}$ | total power dissipation | - | 600 | mW |
| $\mathrm{T}_{\text {stg }}$ | storage temperature | -65 | +150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{j}}$ | junction temperature | - | 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {amb }}$ | operating ambient temperature | -40 | +85 | ${ }^{\circ} \mathrm{C}$ |

THERMAL CHARACTERISTICS

| SYMBOL | PARAMETER | VALUE | UNIT |
| :--- | :--- | :---: | :---: |
| $\mathrm{R}_{\mathrm{th}(j-\mathrm{s})}$ | thermal resistance from junction to solder point | tbf | K/W |
| $\mathrm{R}_{\mathrm{th}(j-\mathrm{a})}$ | thermal resistance from junction to ambient | tbf | K/W |

## CHARACTERISTICS

For typical values $\mathrm{T}_{\mathrm{amb}}=25^{\circ} \mathrm{C}$ and $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$; minimum and maximum values are valid over the entire ambient temperature range and process spread.

| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {CC }}$ | supply voltage |  | 3 | 5 | 5.5 | V |
| $\mathrm{I}_{\text {CCD }}$ | digital supply current | note 1 | 13 | 20 | 28 | mA |
|  |  | note 2 | - | 47 | - | mA |
|  |  | note 3 | 11 | 17 | 24 | mA |
| ICCA | analog supply current |  | 24 | 36 | 51 | mA |
| $\mathrm{P}_{\text {tot }}$ | total power dissipation |  | - | - | 525 | mW |
| $\mathrm{T}_{\mathrm{j}}$ | junction temperature |  | -40 | - | +110 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {amb }}$ | operating ambient temperature |  | -40 | +25 | +85 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{R}_{\mathrm{tr}}$ | small-signal transresistance of the receiver | measured differentially <br> PECL outputs <br> CML outputs |  | $\begin{aligned} & 2000 \\ & 1000 \end{aligned}$ | $-$ | $\begin{aligned} & \mathrm{k} \Omega \\ & \mathrm{k} \Omega \end{aligned}$ |
| $\mathrm{f}_{-3 \mathrm{~dB}(\mathrm{~h})}$ | high frequency -3 dB point | pin BWC left unconnected; note 4 | - | 120 | - | MHz |
| $\mathrm{f}_{-3 \mathrm{~dB}(1)}$ | low frequency -3 dB point |  | 20 | 30 | 40 | kHz |
| $\mathrm{In}_{\text {(tot) }}$ | total integrated RMS noise current over bandwidth | referenced to input; $\begin{gathered} \mathrm{C}_{\mathrm{i}}=1.2 \mathrm{pF} ; \text { note } 5 \\ \Delta \mathrm{f}=90 \mathrm{MHz} \\ \Delta \mathrm{f}=120 \mathrm{MHz} \\ \Delta \mathrm{f}=155 \mathrm{MHz} \end{gathered}$ | - | 16 <br> tbf <br> tbf |  | nA <br> nA <br> nA |
| PSRR | power supply rejection ratio | measured differentially; note 6 $\begin{aligned} & f=100 \mathrm{kHz} \text { to } 10 \mathrm{MHz} \\ & \mathrm{f}=10 \mathrm{MHz} \text { to } 100 \mathrm{MHz} \end{aligned}$ | - | $\begin{aligned} & 0.5 \\ & 10 \end{aligned}$ |  | $\mu \mathrm{A} / \mathrm{V}$ <br> $\mu \mathrm{A} / \mathrm{V}$ |
| $\Delta \mathrm{R}_{\mathrm{tr}} / \Delta \mathrm{t}$ | AGC loop constant |  | - | 1 | - | dB/ms |
| Input: IPhoto |  |  |  |  |  |  |
| $\mathrm{V}_{\text {bias(IPhoto) }}$ | input bias voltage |  | tbf | 1048 | tbf | mV |
| $\mathrm{I}_{\text {(IPhoto)(p-p) }}$ | input current (peak-to-peak value) | $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$ | -2000 | +1 | +2000 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{CC}}=3.3 \mathrm{~V}$ | -1000 | +1 | +1000 | $\mu \mathrm{A}$ |

## PECL outputs: OUTPECL and OUTQPECL

| $\mathrm{V}_{\mathrm{OH}}$ | HIGH-level output voltage | $50 \Omega$ to $\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$ | $\mathrm{~V}_{\mathrm{CC}}-1100$ | - | $\mathrm{V}_{\mathrm{CC}}-900$ | mV |
| :--- | :--- | :--- | :--- | :--- | :--- | :--- |
| $\mathrm{V}_{\mathrm{OL}}$ | LOW-level output voltage | $50 \Omega$ to $\mathrm{V}_{\mathrm{CC}}-2 \mathrm{~V}$ | $\mathrm{~V}_{\mathrm{CC}}-1840$ | - | $\mathrm{V}_{\mathrm{CC}}-1620$ | mV |
| $\mathrm{V}_{\mathrm{OO}}$ | output offset voltage | measured differentially | -10 | - | +10 | mV |
| $\mathrm{t}_{\mathrm{r}}$ | rise time | $20 \%$ to $80 \%$ | - | tbf | tbf | ps |
| $\mathrm{t}_{\mathrm{f}}$ | fall time | $80 \%$ to $20 \%$ | - | tbf | tbf | ps |


| SYMBOL | PARAMETER | CONDITIONS | MIN. | TYP. | MAX. | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| PECL outputs: LOS and LOSQ |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{OH}}$ | HIGH-level output voltage | $50 \Omega$ to $\mathrm{V}_{C C}-2 \mathrm{~V}$ | $\mathrm{V}_{C C}-1100$ | - | $\mathrm{V}_{\mathrm{CC}}-900$ | mV |
| $\mathrm{V}_{\mathrm{OL}}$ | LOW-level output voltage | $50 \Omega$ to $\mathrm{V}_{C C}-2 \mathrm{~V}$ | $\mathrm{V}_{C C}-1840$ | - | $\mathrm{V}_{C C}-1620$ | mV |
| $\mathrm{V}_{\mathrm{OO}}$ | output offset voltage | measured differentially | -10 | - | +10 | mV |
| $\mathrm{tr}_{\mathrm{r}}$ | rise time | 20\% to 80\% | - | - | 600 | ns |
| $\mathrm{t}_{\mathrm{f}}$ | fall time | 80\% to 20\% | - | - | 200 | ns |
| CML outputs: OUTCML and OUTQCML |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{O}}$ | output voltage | measured single-ended; $50 \Omega$ to $V_{C C}$ | $\mathrm{V}_{\mathrm{CC}}-260$ | - | $\mathrm{V}_{\text {CC }}$ | mV |
| $\mathrm{V}_{\text {o(se)(p-p) }}$ | output voltage single-ended (peak-to-peak value) | $50 \Omega$ to $\mathrm{V}_{\text {CC }}$ | 150 | 200 | 260 | mV |
| $\mathrm{V}_{\mathrm{OO}}$ | output offset voltage | measured differentially; $50 \Omega$ to $V_{C C}$ | -10 | - | +10 | mV |
| $\mathrm{R}_{0}$ | output resistance | measured single-ended | 80 | 100 | 120 | $\Omega$ |
| $\mathrm{tr}_{\mathrm{r}}$ | rise time | $\begin{aligned} & 20 \% \text { to } 80 \% ; \\ & R_{\mathrm{L}}=50 \Omega ; \mathrm{C}_{\mathrm{L}}=1 \mathrm{pF} \end{aligned}$ | - | tbf | - | ps |
| $\mathrm{t}_{\mathrm{f}}$ | fall time | $\begin{aligned} & 80 \% \text { to } 20 \% ; \\ & R_{\mathrm{L}}=50 \Omega ; \mathrm{C}_{\mathrm{L}}=1 \mathrm{pF} \\ & \hline \end{aligned}$ | - | tbf | - | ps |
| CMOS input: OUTSEL |  |  |  |  |  |  |
| $\mathrm{V}_{\text {IL }}$ | LOW-level input voltage |  | - | 0.4 | 0.8 | V |
| $\mathrm{V}_{\mathrm{IH}}$ | HIGH-level input voltage |  | $\mathrm{V}_{\mathrm{CC}}-1$ | $\mathrm{V}_{\mathrm{CC}}-0.5$ | - | V |
| CMOS output: LOSTTL |  |  |  |  |  |  |
| $\mathrm{V}_{\mathrm{OL}}$ | LOW-level output voltage |  | 0 | - | 0.2 | V |
| $\mathrm{V}_{\mathrm{OH}}$ | HIGH-level output voltage |  | $\mathrm{V}_{\mathrm{CC}}-0.2$ | - | $\mathrm{V}_{\mathrm{CC}}$ | V |

## Notes

1. OUTPECL, OUTQPECL, OUTCML, OUTQCML, LOS and LOSQ outputs are left unconnected. OUTPECL and OUTQPECL outputs are active.
2. OUTPECL and OUTQPECL outputs are terminated with $50 \Omega$ to $\mathrm{V}_{\mathrm{T}}$. $\mathrm{V}_{\mathrm{T}}$ is an external termination voltage for PECL outputs and is 2 V below the supply voltage. OUTCML, OUTQCML, LOS and LOSQ outputs are left unconnected.
3. OUTCML and OUTQCML outputs are terminated with $50 \Omega$ to $V_{C C D}$; CML outputs are active. OUTPECL, OUTQPECL, LOS and LOSQ outputs are left unconnected.
4. The bandwidth is set to 120 MHz by default. It can be varied between 90 and 150 MHz by adjusting the voltage at pin BWC.
5. All $\mathrm{I}_{\mathrm{n} \text { (tot) }}$ measurements were made with an input capacitance of $\mathrm{C}_{\mathrm{i}}=1.2 \mathrm{pF}$. This was comprised of 0.7 pF for the photodiode itself, with 0.3 pF allowed for the PCB layout and 0.2 pF intrinsic to the package.
6. PSRR is defined as the ratio of the equivalent current change at the input ( $\Delta \|_{\mathrm{I} \text { Photo }}$ ) to a change in supply voltage: PSRR $=\frac{\Delta I_{\text {IPhoto }}}{\Delta \mathrm{V}_{\mathrm{CC}}}$
For example, a 4 mV disturbance on $\mathrm{V}_{\mathrm{CC}}$ at 10 MHz will typically generate the equivalent of 2 nA extra photodiode current.

## APPLICATION INFORMATION



Fig. 6 Application diagram: PECL data outputs active.


Fig. 7 Application diagram: CML data outputs active.

## PECL outputs: OUTPECL, OUTQPECL, LOS and LOSQ

PECL outputs can be terminated in different ways depending on the power supply voltage (see Fig.8).



Fig. 8 PECL termination schemes.

## CML outputs: OUTCML and OUTQCML

The output impedance of the CML output driver is $100 \Omega$ (see Fig.9) which doesn't match the characteristic impedance of the strip line. While this means that the reflections of some incident edges will arrive at the driver output on the PCB, this value was selected to reduce power dissipation inside the IC. The parallel combination of $100 \Omega$ and $50 \Omega(33 \Omega)$ will generate a signal swing of 200 mV (peak-to-peak value, single-sided) with a tail current of 6 mA .

If the output impedance was $50 \Omega$ rather than $100 \Omega$, an 8 mA tail current would be needed to generate the same voltage swing. This would increase power dissipation by 33\%.
If necessary, the output impedance of the generator can be matched to the line impedance by connecting an external $100 \Omega$ resistor in parallel with the output as shown in Fig.10. The magnitude of the output voltage swing will not change due to adaptive regulation. However, power dissipation will increase by $33 \%$.


## PACKAGE OUTLINE

LQFP32: plastic low profile quad flat package; 32 leads; body $5 \times 5 \times 1.4 \mathrm{~mm}$
SOT401-1

detail X


DIMENSIONS (mm are the original dimensions)

| UNIT | $\begin{gathered} \mathrm{A} \\ \max . \end{gathered}$ | $\mathrm{A}_{1}$ | $\mathrm{A}_{2}$ | $\mathrm{A}_{3}$ | $\mathrm{b}_{\mathrm{p}}$ | c | $D^{(1)}$ | $E^{(1)}$ | e | $H_{D}$ | $\mathrm{H}_{\mathrm{E}}$ | L | $\mathrm{L}_{\mathrm{p}}$ | v | w | y | $Z_{\text {D }}{ }^{(1)}$ | $Z_{E}{ }^{(1)}$ | $\theta$ |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| mm | 1.60 | $\begin{aligned} & 0.15 \\ & 0.05 \end{aligned}$ | $\begin{aligned} & 1.5 \\ & 1.3 \end{aligned}$ | 0.25 | $\begin{aligned} & 0.27 \\ & 0.17 \end{aligned}$ | $\begin{aligned} & 0.18 \\ & 0.12 \end{aligned}$ | $\begin{aligned} & 5.1 \\ & 4.9 \end{aligned}$ | $\begin{aligned} & 5.1 \\ & 4.9 \end{aligned}$ | 0.5 | $\begin{aligned} & 7.15 \\ & 6.85 \end{aligned}$ | $\begin{aligned} & 7.15 \\ & 6.85 \end{aligned}$ | 1.0 | $\begin{aligned} & 0.75 \\ & 0.45 \end{aligned}$ | 0.2 | 0.12 | 0.1 | $\begin{aligned} & 0.95 \\ & 0.55 \end{aligned}$ | $\begin{aligned} & 0.95 \\ & 0.55 \end{aligned}$ | $\begin{aligned} & 7^{\circ} \\ & 0^{\circ} \end{aligned}$ |

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

| OUTLINE <br> VERSION | REFERENCES |  |  |  | EUROPEAN <br> PROJJECTION | ISSUE DATE |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  | IEC | JEDEC | EIAJ |  |  |  |

## SOLDERING

## Introduction

There is no soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and surface mounted components are mixed on one printed-circuit board. However, wave soldering is not always suitable for surface mounted ICs, or for printed-circuits with high population densities. In these situations reflow soldering is often used.

This text gives a very brief insight to a complex technology. A more in-depth account of soldering ICs can be found in our "Data Handbook IC26; Integrated Circuit Packages" (order code 9398652 90011).

## Reflow soldering

Reflow soldering techniques are suitable for all LQFP packages.

Reflow soldering requires solder paste (a suspension of fine solder particles, flux and binding agent) to be applied to the printed-circuit board by screen printing, stencilling or pressure-syringe dispensing before package placement.

Several methods exist for reflowing; for example, infrared/convection heating in a conveyor type oven. Throughput times (preheating, soldering and cooling) vary between 50 and 300 seconds depending on heating method. Typical reflow peak temperatures range from 215 to $250^{\circ} \mathrm{C}$.

## Wave soldering

Wave soldering is not recommended for LQFP packages. This is because of the likelihood of solder bridging due to closely-spaced leads and the possibility of incomplete solder penetration in multi-lead devices.

| CAUTION |
| :--- |
| Wave soldering is NOT applicable for all LQFP <br> packages with a pitch (e) equal or less than 0.5 mm. |

## If wave soldering cannot be avoided, for LQFP packages with a pitch (e) larger than 0.5 mm , the following conditions must be observed:

- A double-wave (a turbulent wave with high upward pressure followed by a smooth laminar wave) soldering technique should be used.
- The footprint must be at an angle of $45^{\circ}$ to the board direction and must incorporate solder thieves downstream and at the side corners.

During placement and before soldering, the package must be fixed with a droplet of adhesive. The adhesive can be applied by screen printing, pin transfer or syringe dispensing. The package can be soldered after the adhesive is cured.

Maximum permissible solder temperature is $260^{\circ} \mathrm{C}$, and maximum duration of package immersion in solder is 10 seconds, if cooled to less than $150^{\circ} \mathrm{C}$ within 6 seconds. Typical dwell time is 4 seconds at $250^{\circ} \mathrm{C}$.

A mildly-activated flux will eliminate the need for removal of corrosive residues in most applications.

## Repairing soldered joints

Fix the component by first soldering two diagonallyopposite end leads. Use only a low voltage soldering iron (less than 24 V ) applied to the flat part of the lead. Contact time must be limited to 10 seconds at up to $300^{\circ} \mathrm{C}$. When using a dedicated tool, all other leads can be soldered in one operation within 2 to 5 seconds between 270 and $320^{\circ} \mathrm{C}$.

## DEFINITIONS

| Data sheet status |  |
| :--- | :--- |
| Objective specification | This data sheet contains target or goal specifications for product development. |
| Preliminary specification | This data sheet contains preliminary data; supplementary data may be published later. |
| Product specification | This data sheet contains final product specifications. |
| Limiting values | Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or <br> more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation <br> of the device at these or at any other conditions above those given in the Characteristics sections of the specification <br> is not implied. Exposure to limiting values for extended periods may affect device reliability. |

## Application information

Where application information is given, it is advisory and does not form part of the specification.

## LIFE SUPPORT APPLICATIONS

These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips for any damages resulting from such improper use or sale.

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